

Notice of References Cited

Application/Control No.

09/964,515

Applicant(s)/Patent Under
Reexamination
KIMURA ET AL.

Examiner

A. M. Thompson

Art Unit

2825

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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